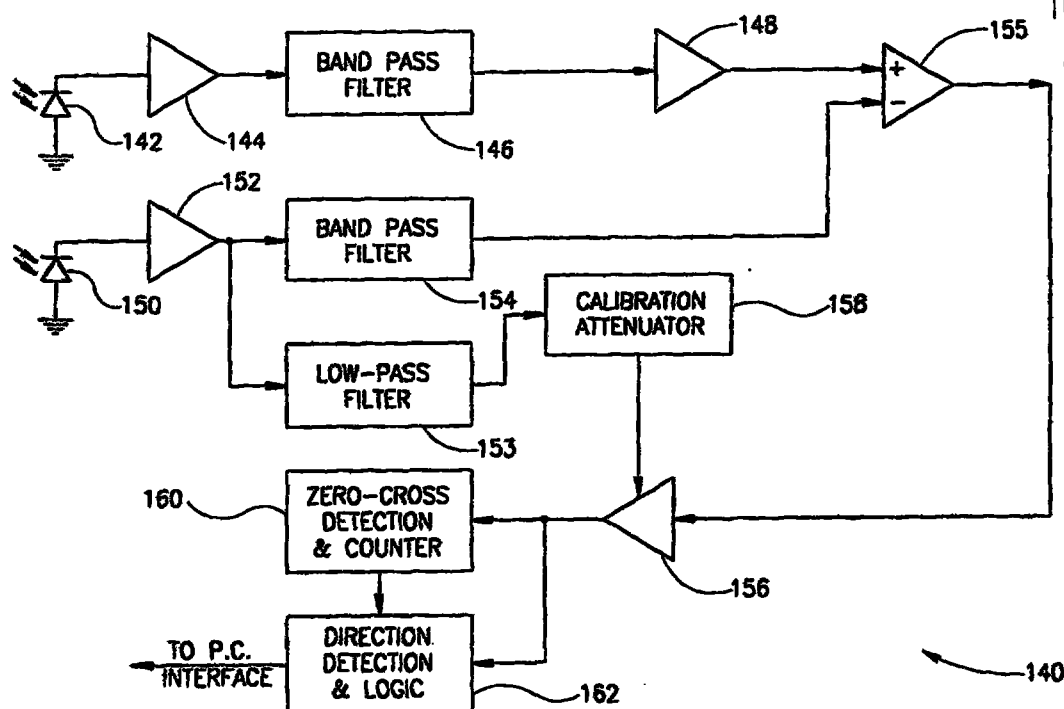




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(71) Applicant (for all designated States except US): OTM TECHNOLOGIES, LTD. [CY/CY]; 11 Bouboulinas Street, Nicosia 1060 (CY).		Published With international search report. / Before the expiration of the time limit for amending the claims and to be republished in the event of the receipt of amendments.	
(72) Inventors; and (75) Inventors/Applicants (for US only): KINROT, Opher [IL/IL]; Herzel Street 22, 43354 Raanana (IL); KINROT, Uri [IL/IL]; Hador Street 25, 45268 Hod-Hasharon (IL); LEDERER, Gilad [IL/IL]; Alvimim Street 7, 69690 Tel Aviv (IL). - Changed address (see 18/306)		4 P.D.s. 1 appl. (assignment see PF 24 of 12/12/00) 3 Invs.	
(74) Agents: FENSTER, Paul et al.; Fenster & Company Patent Attorneys, Ltd., P.O. Box 10256, 49002 Petach Tikva (IL).			

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(57) Abstract

A method for determining the relative motion of a surface with respect to a measurement device comprising: illuminating the surface with incident illumination; detecting illumination reflected from the surface to form at least one detected signal; and determining the amount of relative motion parallel to the surface from said at least one detected signal, characterized in that said determining includes correcting for the effects of relative motion perpendicular to the surface.